

※ 考生請注意：本試題 可 不可 使用計算機

- Gallium arsenide at $T=300\text{K}$ contains acceptor impurity atoms at a density of $1 \times 10^{15} \text{cm}^{-3}$. Additional impurity atoms are to be added so that the Fermi level is 0.45eV below the intrinsic level. Determine the concentration and type of impurity atoms to be added. (if $n_i=1.8 \times 10^6 \text{cm}^{-3}$) (9%)
- A geometry for measuring the Hall effect is shown in Fig. 1. A silicon Hall device at $T=300\text{K}$ has the following geometry: $d=10^{-3}\text{cm}$, $W=10^{-2}\text{cm}$, and $L=10^{-1}\text{cm}$. The following parameters are measured: $I_x=0.75\text{mA}$, $V_x=15\text{V}$, $V_H=+5.8\text{mV}$, and $B_z=1000$ gauss. Determine (a) the conductivity type, (b) the majority carrier concentration, and (c) the majority carrier mobility. (11%)

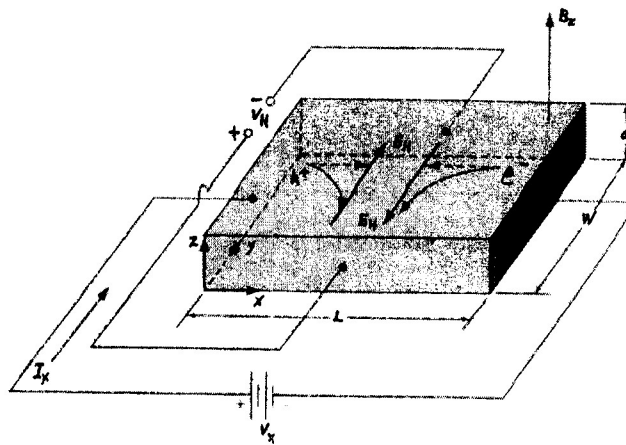


Fig. 1

- The doping concentrations of a silicon p-n junction are $N_A = 10^{17} \text{cm}^{-3}$ on the p-side and $N_D = 10^{16} \text{cm}^{-3}$ on the n-side. Calculate the depletion layer widths in the p-side (x_p) and n-side (x_n) at 300K when a 5V reverse bias is applied. (if $n_i = 10^{10} \text{cm}^{-3}$, silicon dielectric constant 11.9 , and permittivity $\epsilon_0 = 8.85 \times 10^{-14} \text{F/cm}$) (10%)
- The junction capacitance (C_j) of a silicon p-n⁺ one-sided abrupt junction with junction area $10 \mu\text{m}^2$ is shown in the table below.

| reverse bias applied (V) | 0 | 1 | 2 | 3 |
|--------------------------|------------------------|------------------------|------------------------|------------------------|
| C_j (F) | 3.07×10^{-15} | 2.11×10^{-15} | 1.71×10^{-15} | 1.47×10^{-15} |

Calculate the doping concentrations in the p-side (N_A) and n-side (N_D). (15%)

(背面仍有題目,請繼續作答)

系所組別： 微電子工程研究所

考試科目： 固態電子元件

考試日期： 0307，節次： 2

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5. Qualitatively draw the energy band diagram (including Fermi-level E_F) of an n-p-n bipolar junction transistor under the (a) active, (b) saturation, and (c) cutoff modes of operation. Explain your answer. (15%)
6. Please sketch the current-voltage ($I-V$) characteristics of four different types of MOSFETs (n -channel enhancement, n -channel depletion, p -channel enhancement, and p -channel depletion). (10%)
7. Please derive an equation that relates the quantum efficiency (η) of a $p-i-n$ photodiode to its responsivity (R) at a wavelength λ . (15%)
8. An InGaAs Fabry-Perot laser operating at a wavelength (λ) of $1.55 \mu\text{m}$ has a cavity length of $600 \mu\text{m}$. The index of refraction (n) of InGaAsP is 3.39. Derive and then calculate the separation $\Delta\lambda$ between the allowed modes in the longitudinal direction, assuming $dn/d\lambda = 0.85 \mu\text{m}^{-1}$. (15%)